

## FIR10N80FG-VB Datasheet

## N-Channel 800V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	800			
R <sub>DS(on)</sub> at 25 °C (Ω)	$V_{GS} = 10 V$	0.85		
Q <sub>g</sub> max. (nC)	20			
Q <sub>gs</sub> (nC)	2.4			
Q <sub>gd</sub> (nC)	11			
Configuration	Single			

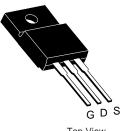
#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

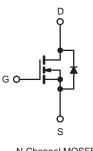
#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial

**TO-220 FULLPAK** 



Top View



ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> :	= 25 °C, unl	less otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V <sub>DS</sub>	800	V
Gate-Source Voltage			V <sub>GS</sub>	± 30	v
Continuous Drain Current (T <sub>1</sub> = 150 °C)	$V_{GS} \text{ at } 10 \text{ V}  \frac{\text{T}_{\text{C}} = 25 \text{ °C}}{\text{T}_{\text{C}} = 100 \text{ °C}}$		L	7	
Continuous Drain Current $(1j = 150^{\circ} C)$	VGS AL TO V	$T_C = 100 \text{ °C}$	I <sub>D</sub>	5.9	А
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	11	
Linear Derating Factor				1.89/1.6/0.4	W/°C
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	86	mJ
Maximum Power Dissipation			PD	99/97/46	W
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		dV/dt	50 st	V/ns
Reverse Diode dV/dt <sup>d</sup>		uv/di	3.2	V/ns	
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for	10 s		300	°C

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD} = 50$  V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.5 A.

c. 1.6 mm from case. d.  $I_{SD} \leq I_D$ , dl/dt = 100 A/µs, starting  $T_J$  = 25 °C.



## FIR10N80FG-VB



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	72	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.7	0/10	

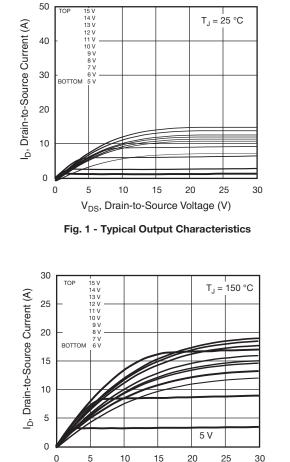
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				•	•	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 250 μA	800	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$		2	-	4	V
	I <sub>GSS</sub>	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
Gate-Source Leakage		$V_{GS} = \pm 30 \text{ V}$		-	-	± 1	μA
		$V_{DS} = 800 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		_	-	1	P
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	_	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	$I_D = 4 \text{ A}$	-	0.85	-	Ω
Forward Transconductance	9 <sub>fs</sub>		$= 30 \text{ V}, \text{ I}_{\text{D}} = 4 \text{ A}$	-	19	-	S
Dynamic	015				I	I	1
Input Capacitance	C <sub>iss</sub>		<u> </u>	-	373	-	[
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$ - 26		-	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	f = 1 MHz	-	14	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	f = 1 MHz V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	46	-	pF
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	64	-	
Total Gate Charge	Qg			-	26		
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 V$	$I_D = 4 \text{ A}, V_{DS} = 520 \text{ V}$	-	2.1	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	2.8	-	]
Turn-On Delay Time	t <sub>d(on)</sub>			-	26	-	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 520 V, $I_D$ = 4 A, $V_{GS}$ = 10 V, $R_g$ = 9.1 $\Omega$		-	55.7	-	- ns
Turn-Off Delay Time	t <sub>d(off)</sub>			-	71	-	
Fall Time	t <sub>f</sub>			-	41	-	
Gate Input Resistance	R <sub>g</sub>	f = 1	MHz, open drain	-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET syml showing the		-	-	7	
Pulsed Diode Forward Current	I <sub>SM</sub>	integral revers p - n junction		-	-	18	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °	C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V	-	-	1.4	V
Reverse Recovery Time	t <sub>rr</sub>			-	192	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = I_S = 4 \text{ A},$		-	μC		
Reverse Recovery Current	I <sub>RRM</sub>	ai/dt = 1	100 A/µs, V <sub>R</sub> = 400 V	_	11	_	A

#### Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

## FIR10N80FG-VB





## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

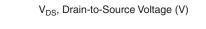


Fig. 2 - Typical Output Characteristics

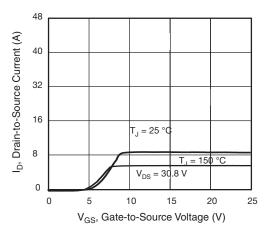


Fig. 3 - Typical Transfer Characteristics

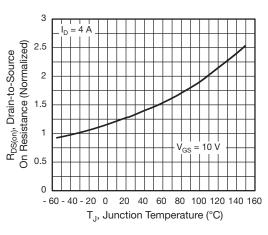


Fig. 4 - Normalized On-Resistance vs. Temperature

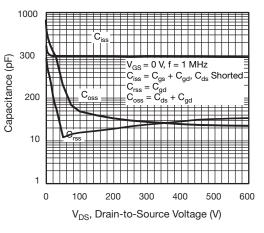


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

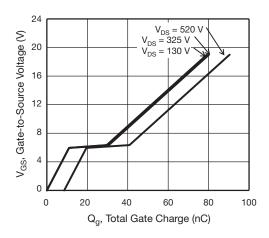


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

## FIR10N80FG-VB



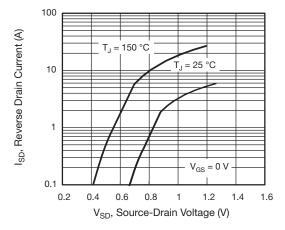


Fig. 7 - Typical Source-Drain Diode Forward Voltage

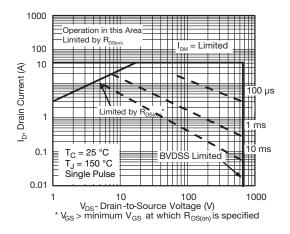


Fig. 8 - Maximum Safe Operating Area

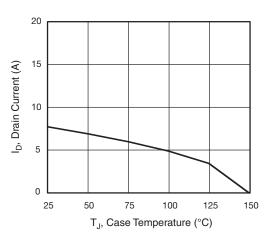


Fig. 9 - Maximum Drain Current vs. Case Temperature

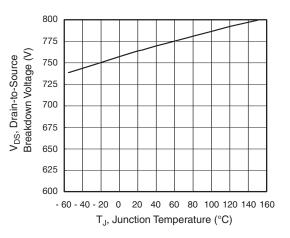


Fig. 10 - Temperature vs. Drain-to-Source Voltage

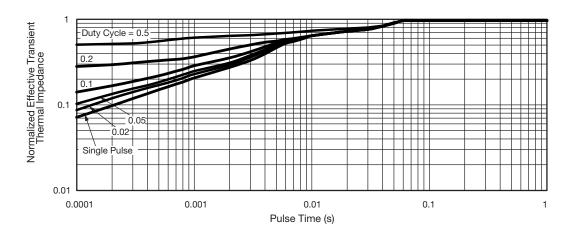


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



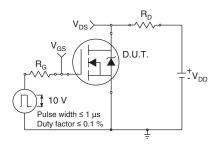


Fig. 12 - Switching Time Test Circuit

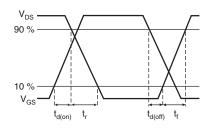


Fig. 13 - Switching Time Waveforms

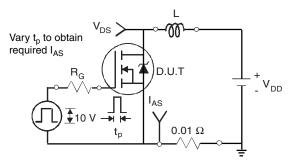


Fig. 14 - Unclamped Inductive Test Circuit

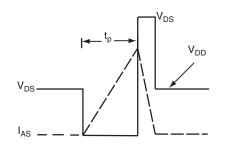


Fig. 15 - Unclamped Inductive Waveforms

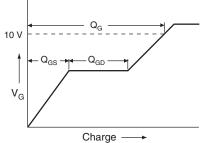


Fig. 16 - Basic Gate Charge Waveform

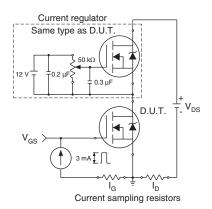
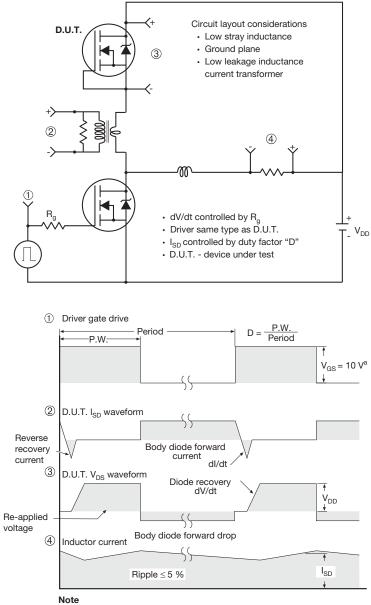


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

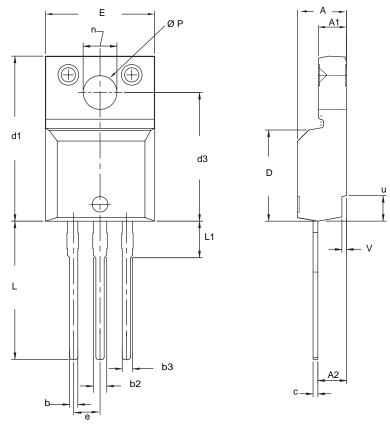


a.  $V_{GS} = 5 V$  for logic level devices

Fig. 18 - For N-Channel



## **TO-220 FULLPAK (HIGH VOLTAGE)**



	MILLI	METERS	INC	CHES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØP	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

#### Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet  $C_{pk} > 1.33$ . 4. All dimensions include burrs and plating thickness. 5. No chipping or package damage.



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